


Schedule of Accreditation

issued by

United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 <p>31545</p> <p>Accredited to ISO/IEC 17025:2017</p>	<p>Princeps Electronics Limited</p> <p>Issue No: 002 Issue date: 27 March 2026</p>	
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<p>Testing performed at the above address only</p>		

DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
<p>ENGINEERING MATERIAL, MACHINERY, STRUCTURES AND PRODUCTS</p> <p>Electronics/Semiconductors</p> <p>Electrical and Electronic (EE) parts to mitigate the risks of receiving or using Suspect/Counterfeit (SC) EE parts</p>	<p><u>Elemental Analysis</u></p> <p>Suspect/Counterfeit Test Evaluation Methods</p> <p>Detection by External Visual Inspection (EVI), Remarking and Resurfacing, and Surface Texture</p> <p>Detection by X-ray Fluorescence (XRF) test methods</p> <p>Detection by Delid/Decapsulation Physical Analysis (DDPA) and developing and using chemical; decapsulation methods</p>	<p>Aerospace Standard SAE AS6171:2018 test methods using the techniques described</p> <p>AS6171/2 REV.A</p> <p>Visual and high magnification inspection to detect recycled or counterfeit parts</p> <p>AS6171/3:</p> <p>Analysis of elements Pb, Cu, Zn, Ni, Ag Sn, Au, Pd to enable the determination of plating layer thicknesses, the presence of barrier materials, and the base material</p> <p>AS6171/4 using:</p> <p>In house Lab procedure 280486 Nisene JetEtch Pro Acid Decapsulation System</p>



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ENGINEERING MATERIAL, MACHINERY, STRUCTURES AND PRODUCTS (cont'd) Electronics/Semiconductors (cont'd) Electrical and Electronic (EE) parts to mitigate the risks of receiving or using Suspect/Counterfeit (SC) EE parts (cont'd)	<u>Elemental Analysis</u> (cont'd) Detection by Radiological (X-ray) test methods	AS6171/5: To examine the internal and external attributes of a part in order to detect deliberate misrepresentation or damage, which could indicate a suspect counterfeit part
END		